

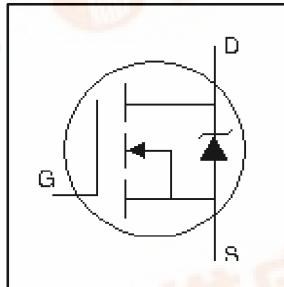
# International IR Rectifier

HEXFET® Power MOSFET

PD -9.1255

**IRL630**

- Dynamic dv/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- $R_{DS(ON)}$  Specified at  $V_{GS} = 4V$  &  $5V$
- $150^{\circ}\text{C}$  Operating Temperature
- Fast Switching
- Ease of paralleling

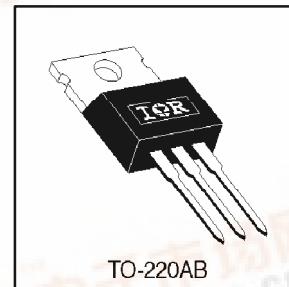


$V_{DSS} = 200\text{V}$   
 $R_{DS(on)} = 0.40\Omega$   
 $I_D = 9.0\text{A}$

## Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



TO-220AB

## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}\text{C}$	Continuous Drain Current, $V_{GS} @ 5.0\text{V}$	9.0	A
$I_D @ T_C = 100^{\circ}\text{C}$	Continuous Drain Current, $V_{GS} @ 5.0\text{V}$	5.7	
$I_{DM}$	Pulsed Drain Current ①	36	
$P_D @ T_C = 25^{\circ}\text{C}$	Power Dissipation	74	W
	Linear Derating Factor	0.59	W/ $^{\circ}\text{C}$
$V_{GS}$	Gate-to-Source Voltage	$\pm 10$	V
$E_{AS}$	Single Pulse Avalanche Energy ②	250	mJ
$I_{AR}$	Avalanche Current ①	9.0	A
$E_{AR}$	Repetitive Avalanche Energy ①	7.4	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ ③	5.0	V/ns
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	$^{\circ}\text{C}$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw.	10 lbf $\cdot$ in (1.1N $\cdot$ m)	

## Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{eJC}$	Junction-to-Case	—	—	1.7	$^{\circ}\text{C/W}$
$R_{eCS}$	Case-to-Sink, Flat, Greased Surface	—	0.50	—	
$R_{eJA}$	Junction-to-Ambient	—	—	62	

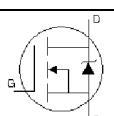
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## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	200	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.27	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{ON})}$	Static Drain-to-Source On-Resistance	—	—	0.40	$\Omega$	$V_{GS} = 5.0V, I_D = 5.4\text{A}$ ④
		—	—	0.50		$V_{GS} = 4.0V, I_D = 4.5\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	1.0	—	2.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$g_f$	Forward Transconductance	4.8	—	—	S	$V_{DS} = 50V, I_D = 5.4\text{A}$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{DS} = 200V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 160V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{GS} = 10V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -10V$
$Q_g$	Total Gate Charge	—	—	40	$\text{nC}$	$I_D = 9.0\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	—	5.5		$V_{DS} = 160V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	24		$V_{GS} = 10V, \text{See Fig. 6 and 13}$ ④
$t_{d(on)}$	Turn-On Delay Time	—	8.0	—	$\text{ns}$	$V_{DD} = 100V$
$t_r$	Rise Time	—	57	—		$I_D = 9.0\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	38	—		$R_G = 6.0\Omega$
$t_f$	Fall Time	—	33	—		$R_D = 11\Omega, \text{See Fig. 10}$ ④
$L_D$	Internal Drain Inductance	—	4.5	—	$\text{nH}$	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{iss}$	Input Capacitance	—	1100	—	$\text{pF}$	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	220	—		$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	—	70	—		$f = 1.0\text{MHz}, \text{See Fig. 5}$

## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	9.0	$A$	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	36		
$V_{SD}$	Diode Forward Voltage	—	—	2.0	V	$T_J = 25^\circ\text{C}, I_S = 9.0\text{A}, V_{GS} = 0V$ ④
$t_{rr}$	Reverse Recovery Time	—	230	350	ns	$T_J = 25^\circ\text{C}, I_F = 9.0\text{A}$
$Q_{rr}$	Reverse Recovery Charge	—	1.7	2.6	$\mu\text{C}$	$dI/dt = 100\text{A}/\mu\text{s}$ ④
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_{S+L_D}$ )				

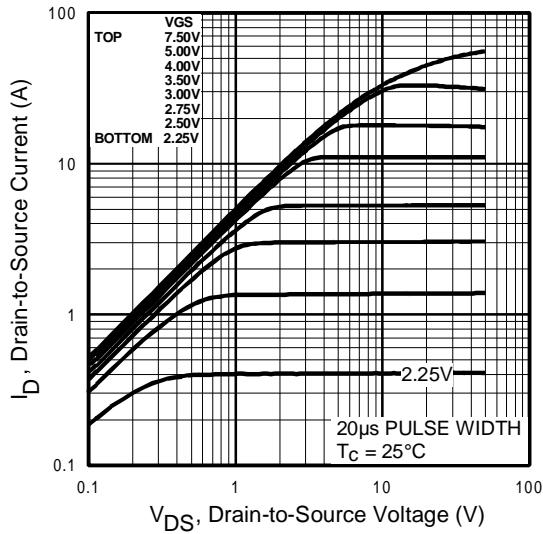
### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )

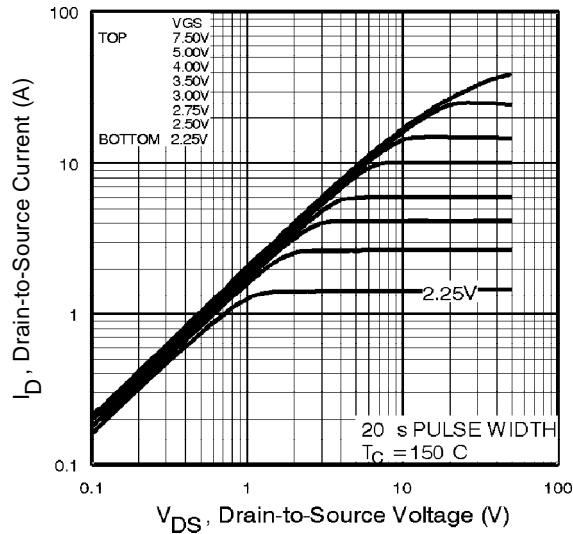
③  $I_{SD} \leq 9.0\text{A}, dI/dt \leq 120\text{A}/\mu\text{s}, V_{DD} \leq V_{(\text{BR})\text{DSS}}, T_J \leq 150^\circ\text{C}$

②  $V_{DD} = 25V$ , starting  $T_J = 25^\circ\text{C}, L = 4.6\text{mH}$   
 $R_G = 25\Omega, I_{AS} = 9.0\text{A}$ . (See Figure 12)

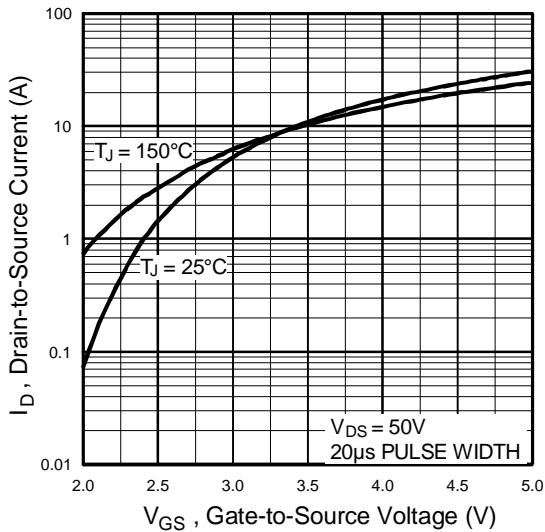
④ Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .

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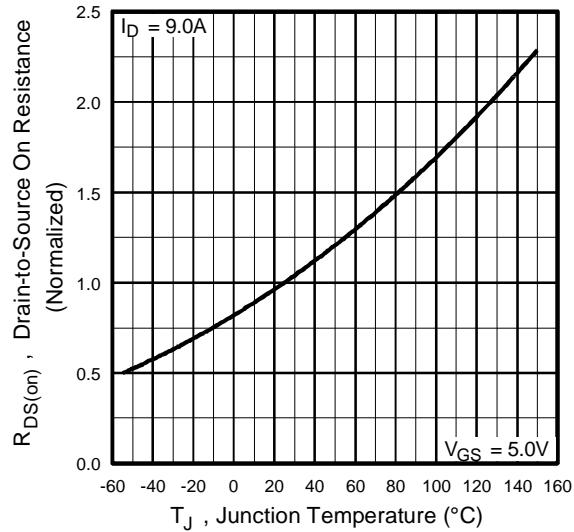
**Fig 1.** Typical Output Characteristics,  
 $T_C = 25^\circ\text{C}$



**Fig 2.** Typical Output Characteristics,  
 $T_C = 150^\circ\text{C}$

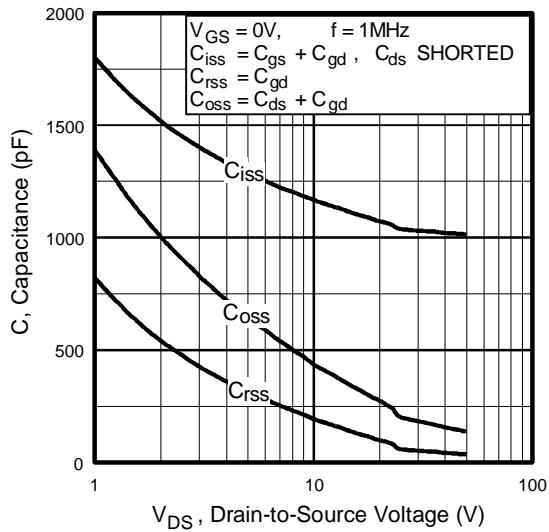


**Fig 3.** Typical Transfer Characteristics

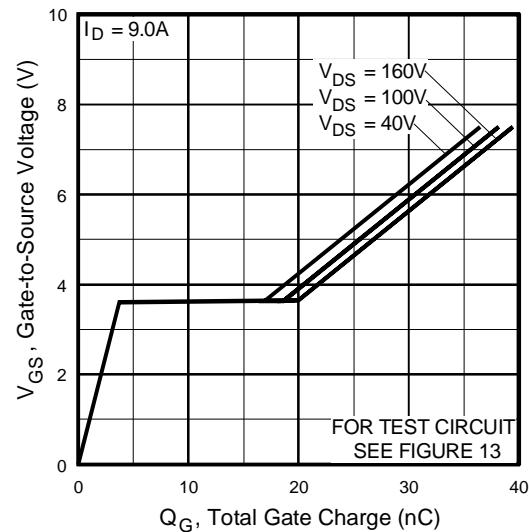


**Fig 4.** Normalized On-Resistance  
Vs. Temperature

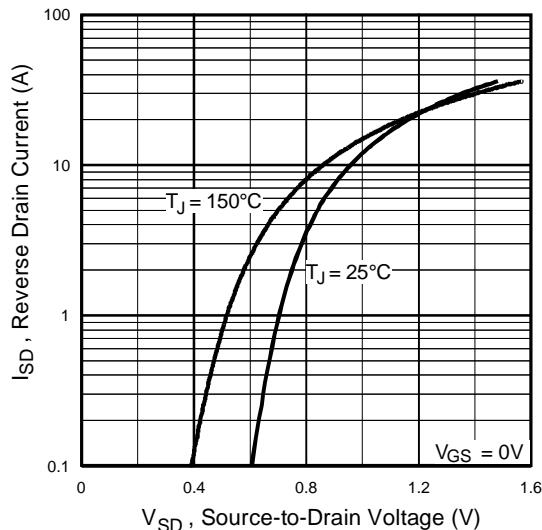
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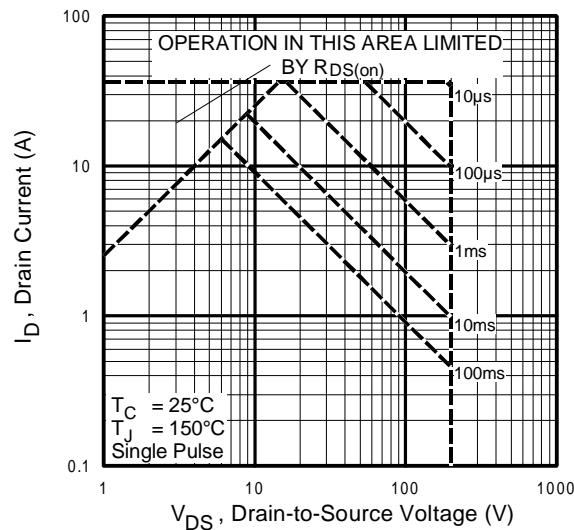
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



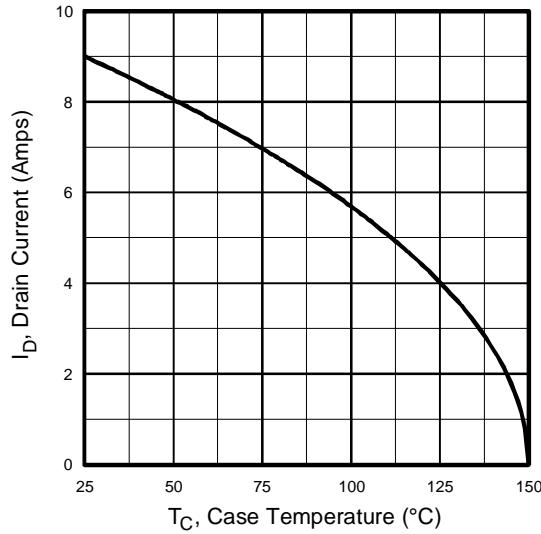
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



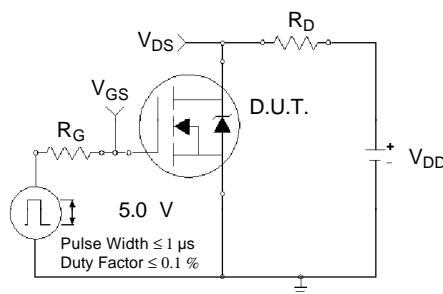
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



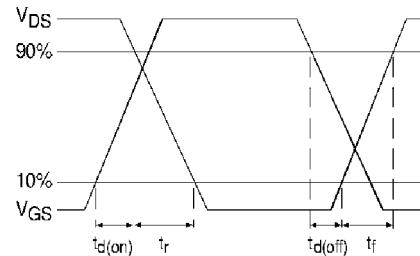
**Fig 8.** Maximum Safe Operating Area

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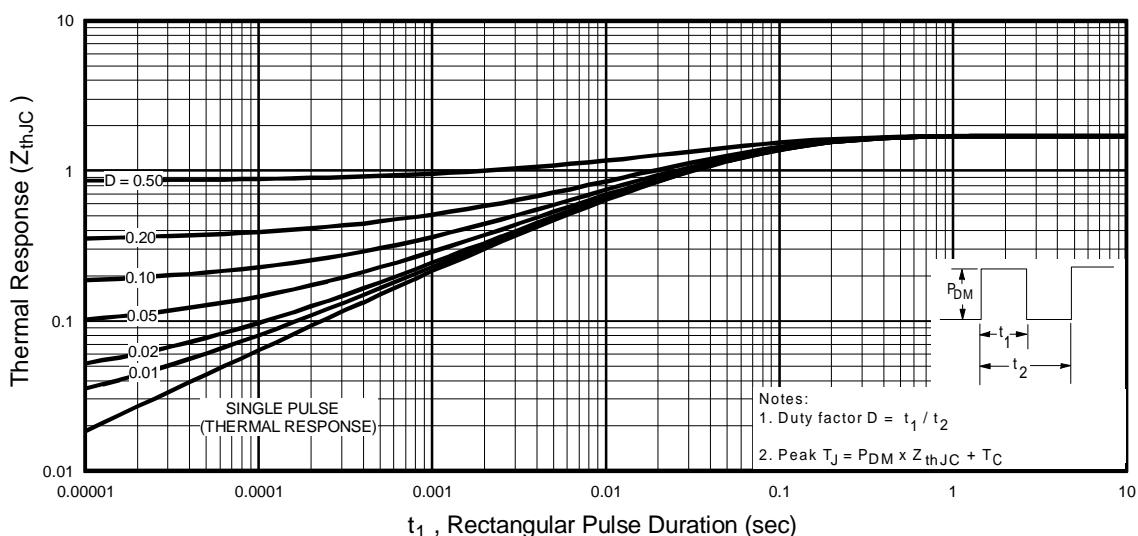
**Fig 9.** Maximum Drain Current Vs.  
Case Temperature



**Fig 10a.** Switching Time Test Circuit



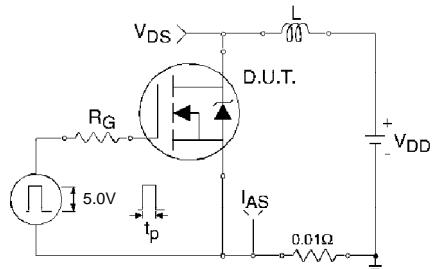
**Fig 10b.** Switching Time Waveforms



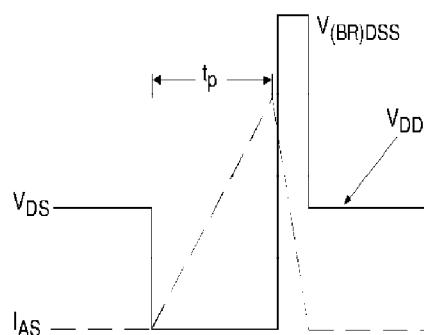
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

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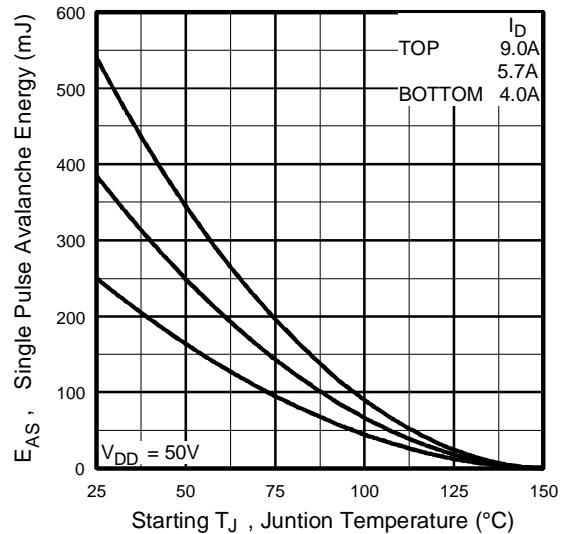
**IR**



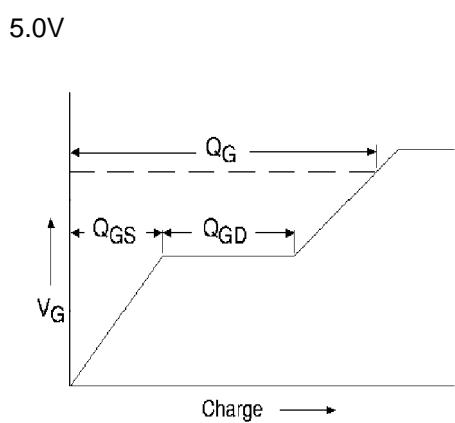
**Fig 12a.** Unclamped Inductive Test Circuit



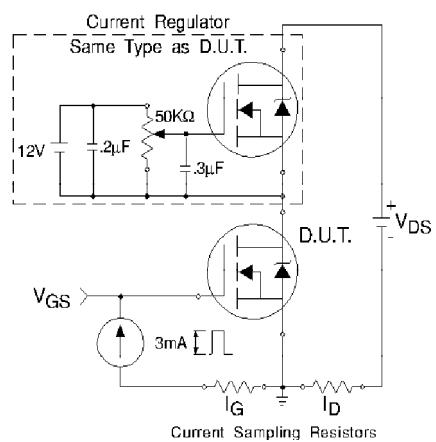
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

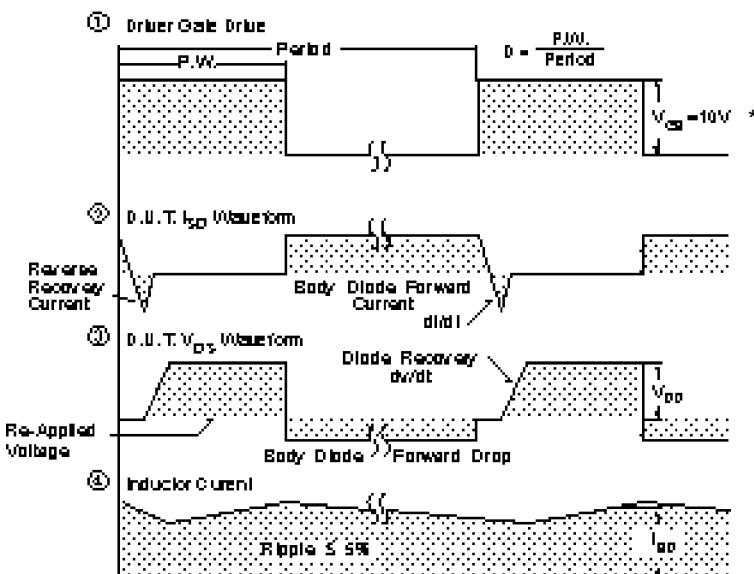
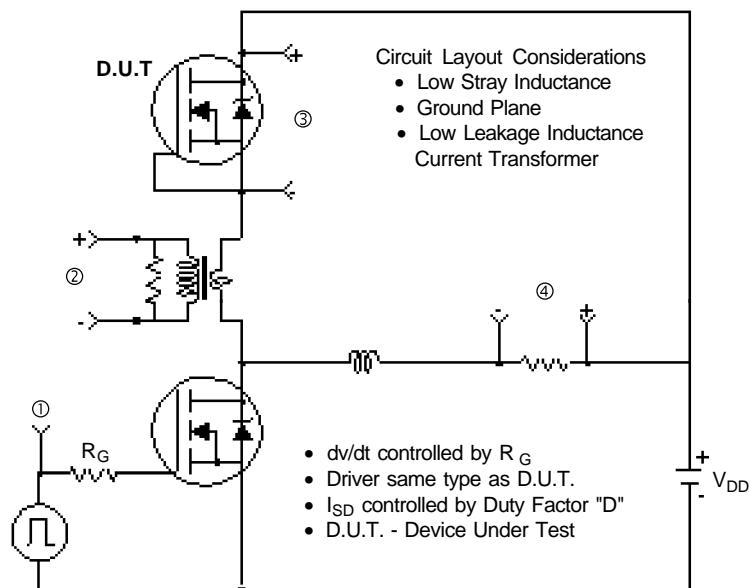


**Fig 13a.** Basic Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit

### Peak Diode Recovery dv/dt Test Circuit



\* VGS = 5V for Logic Level Devices

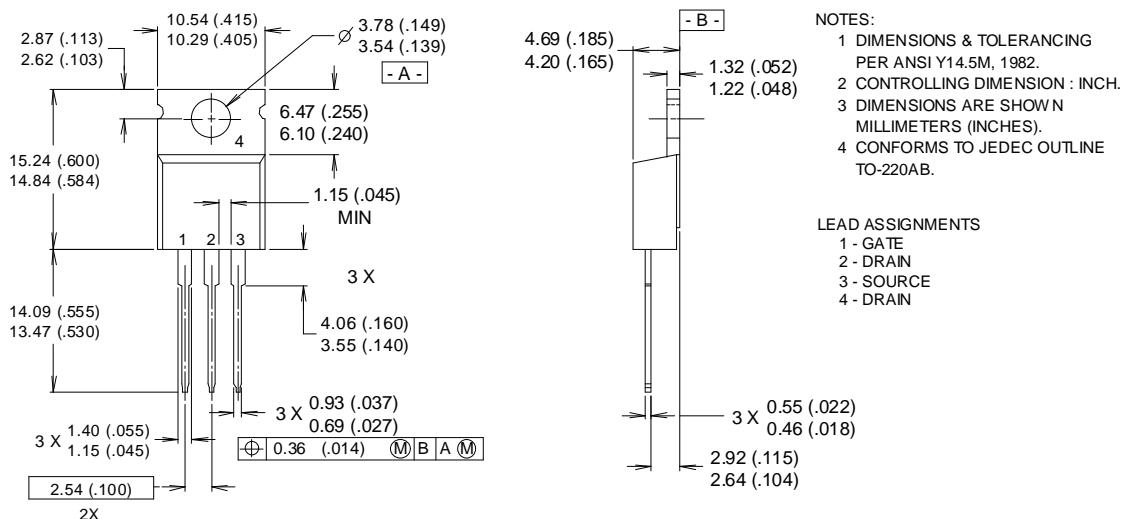
Fig 14. For N-Channel HEXFETs

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## Package Outline

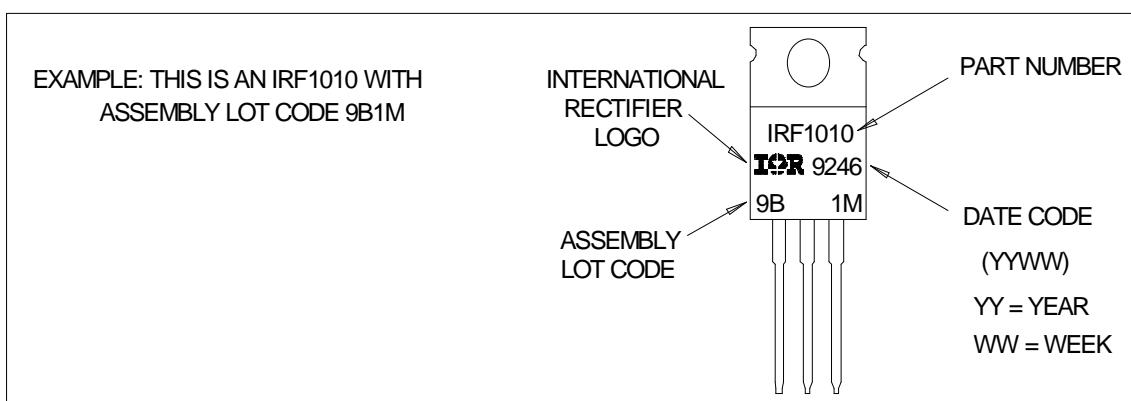
### TO-220AB Outline



CONFORMS TO JEDEC OUTLINE TO-220AB  
Dimensions in Millimeters and (Inches)

## Part Marking Information

TO-220AB



International  
IR Rectifier

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Data and specifications subject to change without notice.